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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/719,648	11/21/2003	Heinz-Peter Frerichs	Micronas.7388	2362
7590	08/23/2005			
Patrick J. O'Shea O'Shea, Getz & Kosakowski, P.C. 1500 Main Street, Suite 912 Springfield, MA 01115			EXAMINER INGHAM, JOHN C	
			ART UNIT	PAPER NUMBER
			2814	

DATE MAILED: 08/23/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

<b>Office Action Summary</b>	<b>Application No.</b> 10/719,648	<b>Applicant(s)</b> FRERICHS, HEINZ-PETER	
	<b>Examiner</b> John C. Ingham	<b>Art Unit</b> 2814	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

### Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
  - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
  - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
  - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

### Status

- 1) ☒ Responsive to communication(s) filed on 21 November 2003.
- 2a) ☐ This action is **FINAL**.                      2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

### Disposition of Claims

- 4) ☒ Claim(s) 1-20 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-20 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

### Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 08 July 2005 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

### Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All    b) ☐ Some \* c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

### Attachment(s)

- |  |   |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892)                        | 4) <input type="checkbox"/> Interview Summary (PTO-413)                     |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)               | Paper No(s)/Mail Date. _____  |
| 3) <input checked="" type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| Paper No(s)/Mail Date <u>21 November 2003</u> <u>2/19/04</u> <u>7/8/05</u>                         | 6) <input type="checkbox"/> Other: _____                                    |

## DETAILED ACTION

### *Priority*

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

### ***Claim Rejections - 35 USC § 103***

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. The factual inquiries set forth in *Graham v. John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

1. Determining the scope and contents of the prior art.
2. Ascertaining the differences between the prior art and the claims at issue.
3. Resolving the level of ordinary skill in the pertinent art.
4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

4. Claims 1-7 and 15-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Frerichs (US 6,929,728), hereinafter "Frerichs '728", in view of Tada (US 6,525,390), hereinafter "Tada". It is noted that Frerichs '728 has a prior publication date of Oct. 31, 2002, which predates the instant application by more than one year.

Regarding claims 1 and 15, Frerichs '728 discloses in Figures 1 and 2 a sensor for measuring an ambient parameter, comprising: a drain (5); a source (2); a channel region (4) disposed between the drain and the source; a conductive guard ring (1) disposed outside the channel region; a sensitive gate layer (8) with a potential that depends on the ambient parameter; and an air gap (10) disposed between the gate layer and the channel region. Furthermore, with regard to claim 1, Frerichs discloses in Figures 1 and 2 a substrate (11) with drain and source disposed thereon.

Frerichs '728 also discloses in Figure 2 an insulating layer (14) disposed between the guard ring (1) and the channel region (4), the insulating layer having a surface (15) on which is disposed a ring structure (7). Frerichs '728 does not, however, specifically disclose the ring structure (7) having a surface conductivity different from a surface conductivity of a remaining portion of the surface of the insulating layer (14).

Tada discloses in Figure 34a a ring structure (207 along with 220, formed of resistive aluminum) having a surface conductivity different from a surface conductivity of a remaining portion (figure 34b, items 211 and 212). Items 211 and 212 in Figure 34b are insulation films, and are of similar structure as the field oxide film (8) in Figure 2. It is well known that field oxide is synonymous with thick silicon dioxide.

It would have been obvious to one of ordinary skill in the art at the time of the invention to improve upon the ring structure of Frerichs '728 by using the teachings of Tada to create a field plate with annular ring structures of a second conductivity type upon it. Motivations to do so include the desirability of having a uniform potential gradient across the field oxide film (Tada col. 18 ln. 16), avoiding voltage concentrations

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between the gate and drain regions, and reduction of the intensity of the electric fields associated with PN junction termination.

Regarding claims 2 and 16, the sensor structure taught by Frerichs '728 in view of Tada (fig. 34a) discloses the sensor of claims 1 and 15, further comprising surface profiling formed with respect to the insulating layer and having at least one elevation (207) and at least one depression (212), and disposed between the guard ring and the channel region. Refer to Tada, figure 4, for the appropriate cross section.

Regarding claims 3 and 20, Frerichs '728 discloses the sensor of claims 2 and 15, further comprising a second insulating layer disposed over the channel region (col. 2 ln. 23).

Regarding claim 4, Tada discloses in figure 34a a ring structure (207 along with 220), which is comprised of an insulating material (resistive aluminum) disposed on the insulating layer (figure 34b, items 211 and 212).

Regarding claim 5, Tada discloses in figure 34a a ring structure (207 along with 220), wherein the ring structure comprises a concentric structure.

Regarding claims 6 and 17, Frerichs '728 discloses the sensor of claims 2 and 15, where the ambient parameter comprises a gas concentration (claim 1 of that patent, see col.2 ln. 1).

Regarding claims 7 and 18, Frerichs '728 discloses the sensor of claims 2 and 15, where the parameter comprises an ion concentration (claim 1 of that patent, see col. 2 ln. 1-2).

Regarding claim 19, Frerichs '728 discloses the sensor of claim 15, where the insulating layer (14) comprises an oxide layer (col. 1, ln. 66-67).

5. Claims 8-14 are rejected under 35 U.S.C. 103(a) as being unpatentable over Frerichs '728 and Tada as applied to claims 1-7 above, and further in view of Paris, R. et al, hereinafter "Paris".

Regarding claim 8, Frerichs '728 discloses in Figures 1 and 2 a sensor for measuring a concentration of an ambient parameter, comprising: a substrate (11); a channel region (4) formed in the substrate; a conductive guard ring (1) arranged outside the channel region; a sensitive gate layer (8) whose potential depends on the concentration of the ambient parameter, an air gap (10) disposed between the gate layer and the channel region; an oxide layer (14) disposed between the guard ring and the channel region, with the surface (13) of the oxide layer having a ring structure (7) arranged thereon. As stated previously, Tada discloses in Figure 34a a ring structure (207 along with 220, formed of resistive aluminum) having a surface conductivity different from a surface conductivity of a remaining portion (figure 34b, items 211 and 212).

The combination of Frerichs '728 and Tada, as applied to claims 1-7 above, does not teach a source and drain forming a field-effect transistor, the transistor being spatially separated from the air gap between the gate layer and the channel region, the transistor having a gate that is connected by an electrode to the channel region.

Paris discloses in figure 1 a source and drain forming a field-effect transistor (item FET in figure), the transistor being spatially separated from the air gap (area bounded by the gate, nitride, and distance pieces) between the gate layer and the channel region (area under the substrate between the guard rings), the transistor having a gate that is connected by an electrode to the channel region.

It would have been obvious to one of ordinary skill in the art at the time of the invention to create a capacitively controlled transistor by adding the teachings of Paris to the device already created by Frerichs '728 and Tada. The motivation to do so includes the positive effect of the CCFET structure in regards to temperature dependency and long term stability (Paris, pg. 424).

Regarding claim 9, Frerichs '728 discloses the sensor of claim 8, where the ambient parameter comprises a gas (claim 1 of that patent, see col.2 ln. 1).

Regarding claim 10, the sensor structure taught by Frerichs '728 in view of Tada (fig. 34a) discloses the sensor of claim 8, further comprising surface profiling formed with respect to the insulating layer and having at least one elevation (207) and at least one depression (212), and disposed between the guard ring and the channel region. Refer to Tada, figure 4, for the appropriate cross section.

Regarding claim 11, Frerichs '728 discloses the sensor of claim 8, further comprising an insulating thin layer disposed over the channel region (col. 2 ln. 23).

Regarding claim 12, Tada discloses in figure 34a a ring structure (207 along with 220), which is comprised of an insulating material (resistive aluminum) disposed on the oxide (figure 34b, items 211 and 212).

Regarding claim 13, Tada discloses in figure 34a a ring structure (207 along with 220), wherein the ring structure comprises a concentric structure.

Regarding claim 14, Frerichs '728 discloses the sensor of claim 8, where the ambient parameter comprises an ion concentration (claim 1 of that patent, see col. 2 ln. 1-2).

### ***Conclusion***

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John C. Ingham whose telephone number is (571) 272-0237. The examiner can normally be reached on M-F, 8am-5pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.


Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).



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GEORGE ECKERT  
PRIMARY EXAMINER